Benchtop EDXRF for rapid, nondestructive elemental analysis

For demanding elemental analysis applications, or for situations where analysis time or sample throughput is critical, Rigaku offers the NEX QC⁺ spectrometer. Employing the next generation silicon detector technology, the enhanced NEX QC⁺ affords significant improvements in elemental peak resolution and counting statistics, resulting in superior calibrations and precision for the most challenging measurements.

- Analyze $^{23}$Na to $^{238}$U non-destructively
- Solids, liquids, alloys, powders and thin films
- 50 kV X-ray tube for wide elemental coverage
- SDD detector for superior resolution and sensitivity
- Modern smartphone style "icon driven" user interface
- Multiple automated tube filters for enhanced sensitivity
- Convenient built-in thermal printer
- Low cost with unmatched performance-to-price ratio
- Optional fundamental parameters

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